

Search Notes

Application/Control No.

10/617,702

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

BAICH ET AL.

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	354	10/6/2005	DB
	353		
	386		
	298		
	302		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR